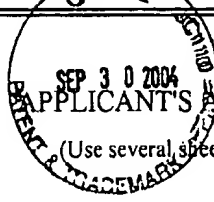
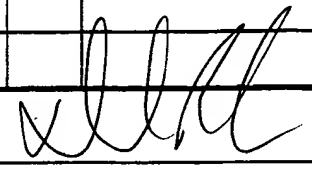
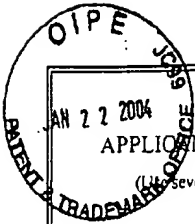


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518 Ed PCT/PIO 2-2 AUG 2001

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		Applicant Donald Dominic ARNONE et al.									
		Filing Date		Group Art Unit							
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Examiner Initial	Document Number				Date						
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									Yes	No	
PCH	0	8	4	1	5	4	8	05/13/98	Europe		
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		Applicant Donald Dominic ARNONE, et. al.					
		Filing Date August 22, 2001		Group Art Unit 3742			
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	US-						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
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PCA		IEEE Journal of Selected Topics in Quantum Electronics, Vol. 2, No. 3, September 1996,					
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Examiner		Date Considered 5-2-2006					
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						Yes	No
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<i>DLR</i>	4.	Zamdmr et al., "On-Chip Frequency-Domain Submillimeter-Wave Transceiver" Appl. Phys. Lett. 75 (24), 12 December 1999, pp. 3877-3879.					
<i>[Signature]</i>							
Examiner		Date Considered 5-2-2005					
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